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The CAFE » General Topics » Importing images from a card reader

The **card reader** works fine. I do not have a problem utilizing it's software to load ... To keep the **degradation** from happening to your original images, ...

www.photoshopcafe.com/cafe/viewthread.php?tid=42706 - 43k - [Cached](#) - [Similar pages](#)

Keith Price Bibliography Character Recognition Systems

Statistical image differences, **degradation** features, and character distance metrics,

Camera based mixed-lingual **card reader** for mobile device, ...

www.visionbib.com/bibliography/char997.html - 42k - [Cached](#) - [Similar pages](#)

Magnetically encodable card having magnetic pigment uniformly ...

Another disadvantage is that continued use of the **card** by swiping the magnetic strip through a **reader** causes **degradation** of the magnetic stripe and ...

www.patentstorm.us/patents/5698839-description.html - 39k - [Cached](#) - [Similar pages](#)

[doc] Proximity Reader Specifications

File Format: Microsoft Word - [View as HTML](#)

Sentinel-Prox™ MM-6800 Access Control Proximity **Card Reader** ... able to mount on metal surfaces with less than 15% **degradation** of the reader's read range. ...

www.awid.com/webresources/documents/products/A&E%20Specs%20-%20MM-6800%20-%20July%202006.doc - [Similar pages](#)

PCMCIA PC Card Reader for DEXIS Digital X-Ray System

DEXIS Digital X-Ray System PC **Card Reader** for desktop computer [PCD-TP-110CS ...

The longer the cable, the more the chance of performance **degradation** due to ...

www.amtron.com/reader/dexis.htm - 30k - [Cached](#) - [Similar pages](#)

SD-1 and Final Cut express? - The Digital Video Information Network

will the express **card reader** for the mac accept that SD **card**? ... MTS to MPEG2 and if there is any **degradation**, I was not able to notice it. ...

dvinfo.net/conf/showthread.php?t=88155 - 48k - [Cached](#) - [Similar pages](#)

[PDF] NACO TWIC Card Reader Comments 03-30-07

File Format: PDF/Adobe Acrobat - [View as HTML](#)

port security plan, not be required to install a TWIC **card reader**. ... Any recommended changes would cost more and possible **degradation** of the end ...

www.nacocharters.org/documents/NACOTWICCardReaderComments03-30-07.pdf - [Similar pages](#)

Newegg.com - RCA DRC257N TV Guardian Divx Memory Card Reader Hdmi ...

The 9-in-2 Flash memory **card reader** supports 9 different memory **card** types in ... can send an all digital, zero-**degradation** signal to you HD ready display. ...

www.newegg.com/Product/Product.aspx?Item=N82E16882125137 - 100k -

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Dispenser Card Reader (POS software) - What does DCR stand for ...

Definition of Dispenser **Card Reader** (POS software) in the list of acronyms and abbreviations ... DCR, **Degradation** Category Rating (ITU-T). DCR, Delay Credit ...

acronyms.thefreedictionary.com/Dispenser+Card+Reader+(POS+software) - 29k -
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Kodak Mkts CF Card

The **card reader**/writer can be quickly attached to a PC to allow camera users to easily ...
without any **degradation** in the quality of the stored images. ...

www.compactflash.org/pr/960912a.HTM - 9k - [Cached](#) - [Similar pages](#)

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(card reader and degradation

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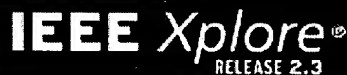
Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1215	(card with (read\$3 or identif\$7 or authenticat\$4)) and (card same (quality or state or attribute or character\$4) same (damage or degrad\$5 or decay))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 12:02
L2	2700	382/135,136,137,138,139,140.ccls. 902/24,25,26.ccls. 340/5.6,5.52,5.53, 5.54,5.82,5.83,5.84.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 11:50
L3	4	1 and 2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 11:50
L4	2322	(card with (read\$3 or identif\$7 or authenticat\$4)) and (card same (quality or state or attribute or character\$4 or condition or quality) same (damage or degrad\$5 or decay or destruct\$3 or destroy\$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 12:03
L5	2700	382/135,136,137,138,139,140.ccls. 902/24,25,26.ccls. 340/5.6,5.52,5.53, 5.54,5.82,5.83,5.84.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 12:39
L6	10	4 and 5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 12:04
L7	1922	(card with read\$3) same (damage or degrad\$5 or decay)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 12:42
L8	11	5 and 7	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 12:39

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L9	499	(card with (read\$3 or verif\$7 or authenticat\$3)) same (quality or state or attribute or character\$4) same (damage or degrad\$5 or decay)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 12:44
L10	0	2 and 9	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 12:44
L11	0	5 and 9	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 12:44
L12	101478	382/135,136,137,138,139,140.ccls. 902/24,25,26.ccls. "235"/\$.ccls. 340/5. 6,5.52,5.53,5.54,5.82,5.83,5.84.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 12:44
L13	79	9 and 12	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 12:45
L14	492	7 and 12	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 12:45

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L1	0	((card same read\$3 same detect\$3 same degrad\$5 same status) and (issu\$3 same communicat\$3 same notice same card same holder)).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 17:28
L2	0	((card same read\$3 same detect\$3 same degrad\$5 same status)).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 17:28
L3	2	((card same read\$3 same detect\$3 same degrad\$5)).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 17:30
L4	3681	((detect\$3 or sens\$3 or configur\$3 or determin\$5 or indicat\$3) with degrad\$).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 17:33
L5	2	(card with read\$3 with (detect\$3 or sens\$3 or configur\$3 or determin\$5 or indicat\$3) with degrad\$).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/06 17:33

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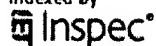
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IET JNL IET Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IET CNF IET Conference Proceeding

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Business of Electronic Product Reliability and Liability, 2004 International Conf
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Aerospace Conference, 2004. Proceedings. 2004 IEEE
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[Nuclear Science, IEEE Transactions on](#)
Volume 52, [Issue 6](#), Part 2, Dec. 2005 Page(s):2866 - 2871
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Ming-Sheng Liu; Hui Liu; Yin-Hua Ma; Wen-Xiong Li;
[Machine Learning and Cybernetics, 2004. Proceedings of 2004 International C](#)
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Hamilton, R.T.; Claus, R.; Grosso, P.; Huffer, M.E.; O'Grady, C.; Scott, I.; Russ
[Real Time Conference, 1999. Santa Fe 1999. 11th IEEE NPSS](#)
14-18 June 1999 Page(s):15 - 18
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